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UNITED STATES PATENT AND TRADEMARK OFFICE

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TC 2800 MAIL ROOM

APPLICANTS: Steven W. Meeks & Rusmin Kudinar
SERIAL NO.: 09/347,622
FILING DATE: July 2, 1999
TITLE: System for Simultaneously Measuring Thin Film Layer Thickness,
Reflectivity, Roughness, Surface Profile and Magnetic Pattern
EXAMINER: T. Nguyen
GROUP ART UNIT: 2877
ATTY. DKT. NO.: 20830-04304; Case 4304 US

14/C
G. Study
5-13-02

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231 on the date shown below.

Dated: 30 April 2002

By: [Signature]
John T. McNelis, Reg. No. 37,186

COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

RESPONSE AND AMENDMENT "B"
UNDER 37 CFR §1.111

Sir:

In response to the Office Action dated 30 January 2002, Applicants submit the following
Amendment and Remarks.